



# 3.3V CMOS QUADRUPLE BUS BUFFER GATE WITH 3-STATE OUTPUTS

**IDT74ALVC125**

## FEATURES:

- 0.5 MICRON CMOS Technology
- ESD > 2000V per MIL-STD-883, Method 3015;  
> 200V using machine model (C = 200pF, R = 0)
- $V_{CC} = 3.3V \pm 0.3V$ , Normal Range
- $V_{CC} = 2.7V$  to  $3.6V$ , Extended Range
- $V_{CC} = 2.5V \pm 0.2V$
- CMOS power levels ( $0.4\mu W$  typ. static)
- Rail-to-Rail output swing for increased noise margin
- Available in SOIC, SSOP and TSSOP packages

## Drive Features for ALVC125:

- High Output Drivers:  $\pm 24mA$
- Suitable for heavy loads

## DESCRIPTION:

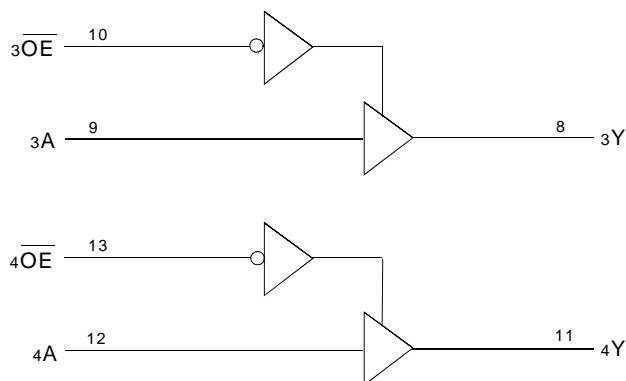
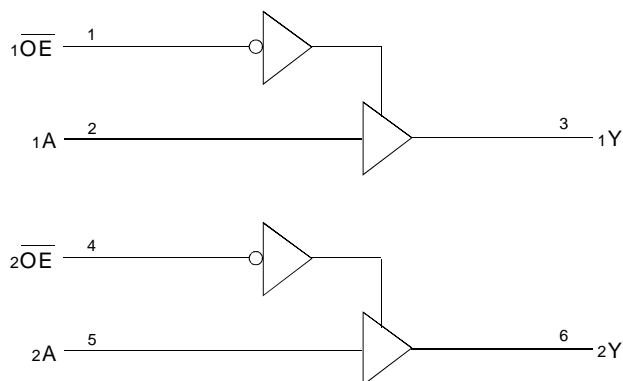
This quadruple bus buffer gate is built using advanced dual metal CMOS technology. The ALVC125 features independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable ( $\overline{OE}$ ) input is high.

The ALVC125 has been designed with a  $\pm 24mA$  output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

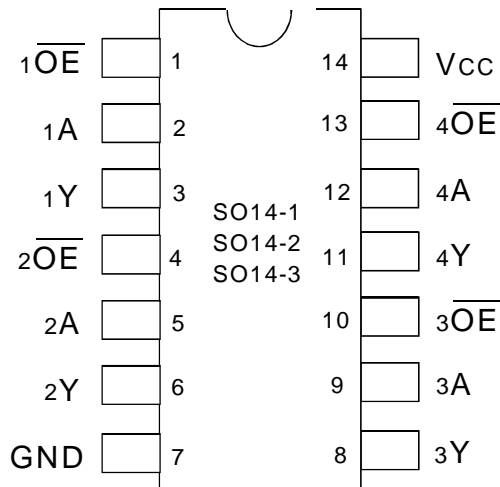
## APPLICATIONS:

- 3.3V High Speed Systems
- 3.3V and lower voltage computing systems

## FUNCTIONAL BLOCK DIAGRAM



## PIN CONFIGURATION



SOIC/ SSOP/ TSSOP  
TOP VIEW

## ABSOLUTE MAXIMUM RATINGS <sup>(1)</sup>

Symbol	Description	Max.	Unit
$V_{TERM}^{(2)}$	Terminal Voltage with Respect to GND	- 0.5 to + 4.6	V
$V_{TERM}^{(3)}$	Terminal Voltage with Respect to GND	- 0.5 to $V_{CC} + 0.5$	V
TSTG	Storage Temperature	- 65 to + 150	°C
I <sub>OUT</sub>	DC Output Current	- 50 to + 50	mA
I <sub>IK</sub>	Continuous Clamp Current, $V_i < 0$ or $V_i > V_{CC}$	± 50	mA
I <sub>OK</sub>	Continuous Clamp Current, $V_o < 0$	- 50	mA
I <sub>CC</sub>	Continuous Current through each	±100	mA
I <sub>SS</sub>	$V_{CC}$ or GND		

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### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- $V_{CC}$  terminals.
- All terminals except  $V_{CC}$ .

## CAPACITANCE (TA = +25°C, f = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Typ.	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$V_{IN} = 0V$	5	7	pF
C <sub>OUT</sub>	Output Capacitance	$V_{OUT} = 0V$	7	9	pF
C <sub>I/O</sub>	I/O Port Capacitance	$V_{IN} = 0V$	7	9	pF

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### NOTE:

- As applicable to the device type.

## PIN DESCRIPTION

Pin Names	Description
$x\overline{OE}$	Output Enable Inputs (Active LOW)
xA	Data Inputs
xY	3-State Outputs

## FUNCTION TABLE (each buffer)<sup>(1)</sup>

Inputs		Output
$x\overline{OE}$	xA	xY
L	H	H
L	L	L
H	X	Z

### NOTE:

- H = HIGH Voltage Level  
L = LOW Voltage Level  
X = Don't Care  
Z = High-Impedance

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$

Symbol	Parameter	Test Conditions		Min.	Typ. <sup>(1)</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Voltage Level	V <sub>CC</sub> = 2.3V to 2.7V		1.7	—	—	V
		V <sub>CC</sub> = 2.7V to 3.6V		2	—	—	
V <sub>IL</sub>	Input LOW Voltage Level	V <sub>CC</sub> = 2.3V to 2.7V		—	—	0.7	V
		V <sub>CC</sub> = 2.7V to 3.6V		—	—	0.8	
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> = 3.6V	V <sub>I</sub> = V <sub>CC</sub>	—	—	± 5	μA
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = 3.6V	V <sub>I</sub> = GND	—	—	± 5	
IoZH	High Impedance Output Current (3-State Output pins)	V <sub>CC</sub> = 3.6V	V <sub>O</sub> = V <sub>CC</sub>	—	—	± 10	μA
IoZL			V <sub>O</sub> = GND	—	—	± 10	μA
V <sub>IK</sub>	Clamp Diode Voltage	V <sub>CC</sub> = 2.3V, I <sub>IN</sub> = - 18mA		—	- 0.7	- 1.2	V
V <sub>H</sub>	Input Hysteresis	V <sub>CC</sub> = 3.3V		—	100	—	mV
I <sub>CC</sub> L	Quiescent Power Supply Current	V <sub>CC</sub> = 3.6V		—	0.1	10	μA
I <sub>CC</sub> H		V <sub>IN</sub> = GND or V <sub>CC</sub>					
ΔI <sub>CC</sub>	Quiescent Power Supply Current Variation	One input at V <sub>CC</sub> - 0.6V, other inputs at V <sub>CC</sub> or GND		—	—	750	μA

**NOTE:**

1. Typical values are at V<sub>CC</sub> = 3.3V, +25°C ambient.

## OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = 2.3V to 3.6V	I <sub>OH</sub> = - 0.1mA	V <sub>CC</sub> - 0.2	—	V
		V <sub>CC</sub> = 2.3V	I <sub>OH</sub> = - 6mA	2	—	
		V <sub>CC</sub> = 2.3V	I <sub>OH</sub> = - 12mA	1.7	—	
		V <sub>CC</sub> = 2.7V		2.2	—	
		V <sub>CC</sub> = 3.0V		2.4	—	
		V <sub>CC</sub> = 3.0V	I <sub>OH</sub> = - 24mA	2	—	
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = 2.3V to 3.6V	I <sub>OL</sub> = 0.1mA	—	0.2	V
		V <sub>CC</sub> = 2.3V	I <sub>OL</sub> = 6mA	—	0.4	
			I <sub>OL</sub> = 12mA	—	0.7	
		V <sub>CC</sub> = 2.7V	I <sub>OL</sub> = 12mA	—	0.4	
		V <sub>CC</sub> = 3.0V	I <sub>OL</sub> = 24mA	—	0.55	

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**NOTE:**

1. V<sub>IH</sub> and V<sub>IL</sub> must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate V<sub>CC</sub> range.  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ .

### OPERATING CHARACTERISTICS, $T_A = 25^\circ\text{C}$

Symbol	Parameter	Test Conditions	$V_{CC} = 2.5V \pm 0.2V$	$V_{CC} = 3.3V \pm 0.3V$	Unit
			Typical	Typical	
CPD	Power Dissipation Capacitance per gate Outputs enabled	$C_L = 0\text{pF}$ , $f = 10\text{MHz}$	20	30	pF
CPD	Power Dissipation Capacitance per gate Outputs disabled		3	6	pF

### SWITCHING CHARACTERISTICS (1)

Symbol	Parameter	$V_{CC} = 2.5V \pm 0.2V$		$V_{CC} = 2.7V$		$V_{CC} = 3.3V \pm 0.3V$		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
$t_{PLH}$ $t_{PHL}$	Propagation Delay xA to xY	1	3.1	1	3.1	1.1	3	ns
$t_{PZH}$ $t_{PZL}$	Output Enable Time $\overline{xOE}$ to xY	1.5	5.4	1.5	5.3	1.5	4.5	ns
$t_{PHZ}$ $t_{PLZ}$	Output Disable Time $\overline{xOE}$ to xY	1	4.1	1.3	4.4	1.7	4.2	ns

**NOTE:**

1. See test circuits and waveforms.  $T_A = -40^\circ\text{C}$  to  $+85^\circ\text{C}$ .

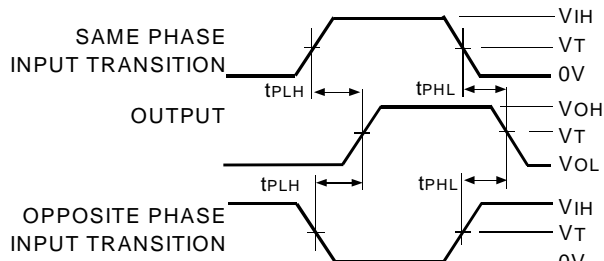
## TEST CIRCUITS AND WAVEFORMS

### TEST CONDITIONS

Symbol	V <sub>CC</sub> (1) = 3.3V ± 0.3V	V <sub>CC</sub> (1) = 2.7V	V <sub>CC</sub> (2) = 2.5V ± 0.2V	Unit
V <sub>LOAD</sub>	6	6	2 x V <sub>CC</sub>	V
V <sub>IH</sub>	2.7	2.7	V <sub>CC</sub>	V
V <sub>T</sub>	1.5	1.5	V <sub>CC</sub> / 2	V
V <sub>LZ</sub>	300	300	150	mV
V <sub>HZ</sub>	300	300	150	mV
C <sub>L</sub>	50	50	30	pF

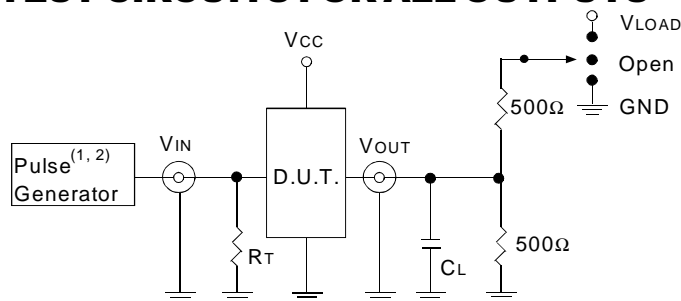
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### PROPAGATION DELAY



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### TEST CIRCUITS FOR ALL OUTPUTS



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#### DEFINITIONS:

C<sub>L</sub> = Load capacitance: includes jig and probe capacitance.  
R<sub>T</sub> = Termination resistance: should be equal to Z<sub>OUT</sub> of the Pulse Generator.

#### NOTES:

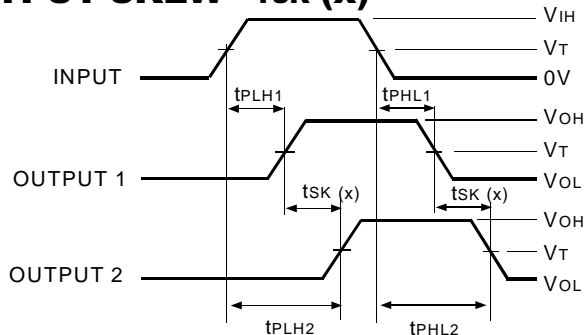
1. Pulse Generator for All Pulses: Rate ≤ 10MHz; t<sub>r</sub> ≤ 2.5ns; t<sub>r</sub> ≤ 2.5ns.
2. Pulse Generator for All Pulses: Rate ≤ 10MHz; t<sub>r</sub> ≤ 2ns; t<sub>r</sub> ≤ 2ns.

### SWITCH POSITION

Test	Switch
Open Drain Disable Low Enable Low	V <sub>LOAD</sub>
Disable High Enable High	GND
All Other tests	Open

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### OUTPUT SKEW - τ<sub>SK</sub> (x)



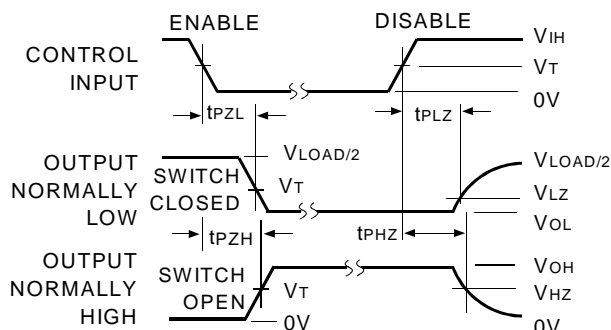
$$\tau_{SK}(x) = |t_{PLH2} - t_{PLH1}| \text{ or } |t_{PHL2} - t_{PHL1}|$$

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#### NOTES:

1. For τ<sub>SK</sub>(o) OUTPUT1 and OUTPUT2 are any two outputs.
2. For τ<sub>SK</sub>(b) OUTPUT1 and OUTPUT2 are in the same bank.

### ENABLE AND DISABLE TIMES

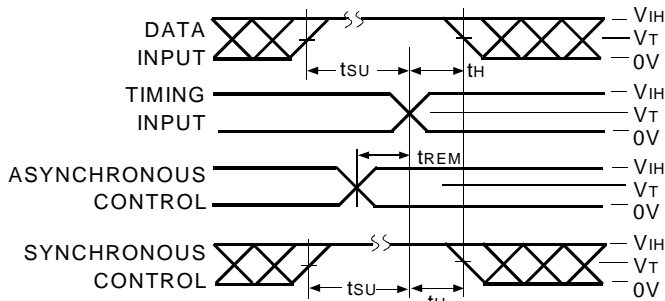


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#### NOTE:

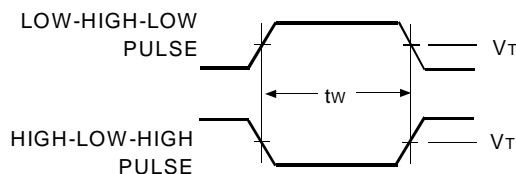
1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

### SET-UP, HOLD, AND RELEASE TIMES



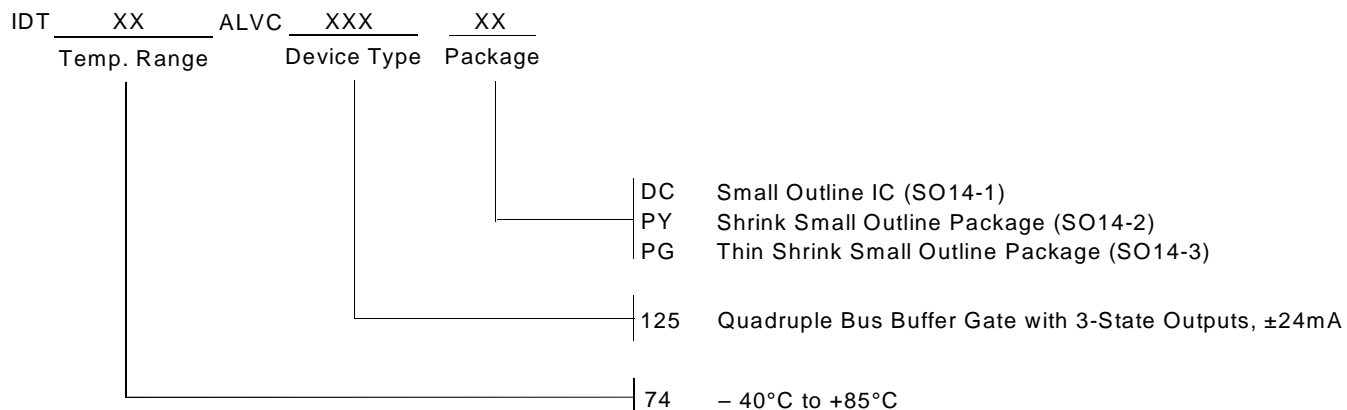
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### PULSE WIDTH



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## ORDERING INFORMATION



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